

**Notice of References Cited**

Application No. 08/835,732	Applicant(s) Klein
Examiner Tiep Nguyen	Group Art Unit 2871

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**U.S. PATENT DOCUMENTS**

	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS
A	4,916,580	4/90	Sano et al.	362	29
B	5,008,658	4/91	Russay et al.	349	58
C	5,128,781	7/92	Ohno et al.	349	65
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K					
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M					

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUBCLASS
N						
O						
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**NON-PATENT DOCUMENTS**

	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
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